

<b>Notice of References Cited</b>	Application/Control No. 10/710,799		Applicant(s)/Patent Under Reexamination CHIN, YUAN-CHANG	
	Examiner M. Lee		Art Unit 2622	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,630,966	10-2003	Tournier, Christian	348/569
*	B	US-6,879,775	04-2005	Takeuchi, Katsuyuki	386/126
*	C	US-5,005,137	04-1991	Ernst, Theodore R.	709/246
*	D	US-2003/0086690	05-2003	Chung et al.	386/69
*	E	US-2004/0081434	04-2004	Jung et al.	386/095
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.